

Page 1, beginning on line 5, insert

-- Background of the Invention:

92 Field of the Invention: --.

Page 3, between lines 2 and 4, insert

93 -- Summary of the Invention: --.

Page 3, delete the paragraph on lines 13-16, reading:

"This object is achieved by means of the features of the subject matter of the independent claims. Advantageous developments of the inventions emerge from the dependent claims."

Page 28, between lines 18 and 20, insert

94 -- Brief Description of the Drawings: --.

Page 30, between lines 3 and 5, insert

95 -- Description of the Preferred Embodiments: --.

Page 30, line 19 through page 31, line 8, replace the paragraph with:

96 -- Electronic devices of this type have the advantage that unevennesses of the surface 3 of the substrate 4 can be compensated over the length of the contact pins 16, by virtue

Q6
end

of the fact that the contact pin 16 can match the unevennesses by bending under plastic and elastic forces. This is particularly advantageous if the contact pin 16 is intended to serve for testing the function of an electronic device on a wafer before the wafer is separated into individual electronic devices or semiconductor chips having an integrated circuit by means of a separation technique. To that end, a test head having contact connection areas which are held by an intermediate carrier and are arranged spatially opposite the contact areas may be pressed onto the contact heads 8 of the contact pins 16, the contact pressure compensating the unevennesses of the substrate 4 and of the intermediate carrier and hence the different distances between the two. --

Page 31, line 22 through page 32, line 2, replace the paragraph with:

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-- Furthermore, the lateral movement of the obliquely arranged contact pin 16 of figure 2 which is triggered when pressure is exerted is also particularly advantageous. The movement contributes to reliable contact-making as a result of the contact point rubbing freely on an opposite contact connection area (not shown) of an intermediate carrier. --

Page 33, lines 1-9, replace the paragraph with:

98 -- In figure 3, a patterned metal layer with passivation layer 15 and uncovered contact areas 1 is applied on the surface 3 of a substrate 4. This patterning of the metal layer and the uncovering of the contact areas 1 may preferably be effected by means of photoresist technology of a closed conductive layer or of a closed passivation layer 15 made of Si_3N_4 . As is shown by figure 4, a closed conductive layer 10 is applied to this passivation layer 15 with uncovered contact areas 1. The layer 10 short-circuits all the contact areas 1. --

Page 34, lines 1-11, replace the paragraph with:

99 -- As shown by figure 7, the through openings 12 are filled with metal by means of electrodeposition, thereby producing a three-dimensionally extending microscopically small contact element 5 which is connected to the contact area 1 in one piece and integrally. In the embodiment as shown by figure 7, the closed conductive layer 10 is made of a copper alloy and an electrodeposited contact pin 16 has a contact head 8 that is made of an adapted copper alloy. The contact head 8, after being formed, is refined by coating with nickel and a gold coating, which are likewise electrodeposited. --

Page 35, lines 13-24, replace the paragraph with:

Q10 --A solder coating placed on the contact heads 8 is preferably used for enabling the contact heads 8 to contact connection areas of an intermediate carrier which carries the rewiring to external electrical connections that are distributed on an area. The electrical connections are usually contact bumps which are formed from solder balls and project in rows and/or columns on one side of the housing, while the housing carries the semiconductor chip on the other side. The connection of the intermediate carrier with rewiring to the contact heads 8 can also be carried out for a multiplicity of contact heads 8 on a wafer and the separation of this assembly into electronic devices can then take place.--

all Page 38, top, change "Patent Claims" to -- We Claim: ---.

Q12 Page 51, top, change "Abstract" to -- Abstract of the
Disclosure: ---.

Page 51, lines 4-5, delete the paragraph reading, "electronic device having microscopically small contact areas and methods for producing it".

Page 51, lines 6-14, replace the paragraph with: